



远勋
YUANXUN

YX120R080 SiC MOSFET



TO-247-3

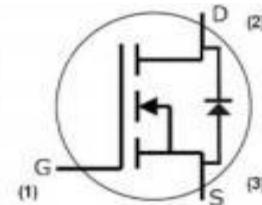
VDS	=	1200	V
RDS(on)_typ	=	80	mΩ
I_D	=	36	A

Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Avalanche Ruggedness

Applications

- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC-DC Converters
- Battery Chargers



Package Parameters

Part Number	Marking	Package
YX120R080T2	YX120R080T2	TO-247-3



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Absolute Maximum Rating

E_{AS}	Avalanche energy	single pulse ($L=10\text{mH}$)	720	mJ
V_{GS}	Gate- Source voltage		-5/+20	V
P_{tot}	Power dissipation	$T_C = 25^\circ\text{C}$	214	W
T_j, T_{stg}	Operating junction and storage temperature		-55 to +175	°C
Symbol	Parameter	Test Conditions	Values	Unit
V_{DS}	Drain- source voltage		1200	V
I_D	Continuous drain current	$T_C = 25^\circ\text{C}$	36	A
		$T_C = 100^\circ\text{C}$	24	A
$I_{D\text{ pulse}}$	Pulsed drain current	$T_C = 25^\circ\text{C}$, t_p limited by $T_{j\text{max}}$	80	A

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	0.70	°C/W
Thermal resistance, junction – ambient. Max	R_{thJA}	40	



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Electric Characteristics (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain- source breakdown voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	1200	-	-	V
$V_{\text{GS(th)}}$	Gate threshold voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=5\text{mA}$	2	3.2		V
I_{DSS}	Zero gate voltage drain current	$V_{\text{DS}}=1200\text{V}, V_{\text{GS}}=0\text{V}$ $T_c=25^\circ\text{C}$	-	1	100	μA
		$V_{\text{DS}}=1200\text{V}, V_{\text{GS}}=0\text{V}$ $T_c=175^\circ\text{C}$	-	5	-	μA
I_{GSS}	Gate- source leakage current	$V_{\text{GS}}=20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	200	nA
$R_{\text{DS(on)}}$	Drain- source on-state resistance	$V_{\text{GS}}=20\text{V}, I_{\text{D}}=10\text{A}$ $T_j=25^\circ\text{C}$	-	80	100	$\text{m}\Omega$
		$V_{\text{GS}}=20\text{V}, I_{\text{D}}=10\text{A}$ $T_j=175^\circ\text{C}$	-	130	-	$\text{m}\Omega$
g_{fs}	Transconductance	$V_{\text{DS}}=20\text{V}, I_{\text{D}}=20\text{A}$	-	12	-	S



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Dynamic Characteristic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{DS} = 800V$ $V_{GS} = 0V$ $f = 1MHz$	-	1272	-	pF
C_{oss}	Output Capacitance		-	75	-	
C_{rss}	Reverse Transfer Capacitance		-	10	-	
Q_G	Gate Total Charge	$V_{DS} = 800V$ $V_{GS} = -5/20V$ $I_D = 20A$	-	79	-	nC
Q_{gs}	Gate- Source charge		-	17	-	
Q_{gd}	Gate- Drain charge		-	43	-	
E_{ON}	Turn-On Switching Energy	$T_J = 25^{\circ}C$, $V_{GS} = -5/20V$, $I_D = 20A$, $V_{DS} = 800V$, $R_g = 15\Omega$, inductive load	-	458	-	μJ
E_{OFF}	Turn-Off Switching Energy		-	348	-	
$t_{d(on)}$	Turn-on delay time		-	19	-	ns
t_r	Rise time		-	74	-	
$t_{d(off)}$	Turn-off delay time		-	29	-	
t_f	Fall time		-	22	-	
R_G	Gate resistance	$V_{GS} = 0V$, $V_{DS} = 0V$, $f = 1MHz$	-	1.7	-	Ω

Body Diode Characteristic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{SD}	Body Diode Forward Voltage	$V_{GS} = -5V$, $I_{SD} = 10A$, $T_J = 25^{\circ}C$		4.2		V
		$V_{GS} = -5V$, $I_{SD} = 10A$, $T_J = 175^{\circ}C$		3.7		
t_{rr}	Body Diode Reverse Recovery Time	$V_{GS} = -5V$, $I_{sd} = 20A$, $dI/dt = 2000A/us$, $V_{ds} = 800V$		24		nS
Q_{rr}	Body Diode Reverse Recovery Charge			152		



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Typical Performance Characteristics

Fig 1. Output Characteristic ($T_J = -55^\circ\text{C}$)

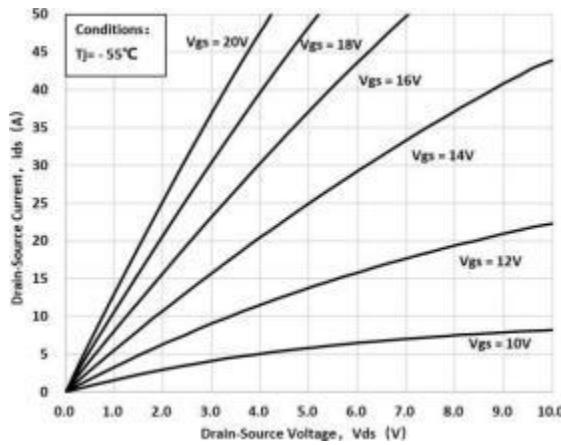


Fig 2. Output Characteristic ($T_J = 25^\circ\text{C}$)

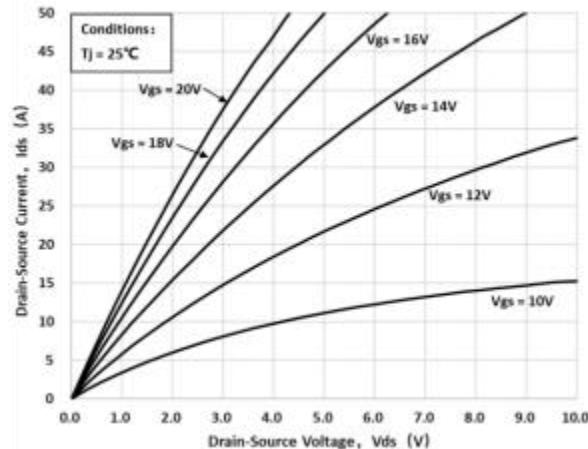


Fig 3. Output Characteristic ($T_J = 175^\circ\text{C}$)

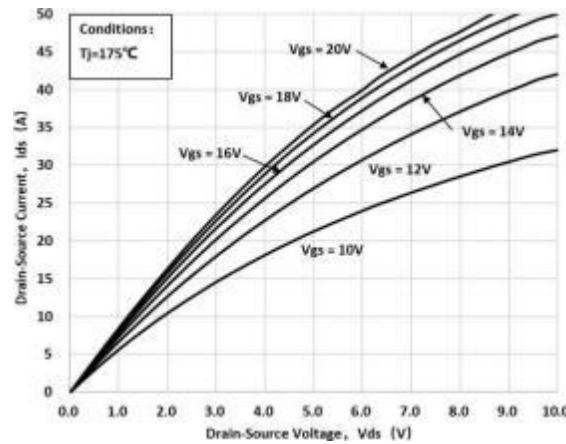


Fig 4: $R_{DS(on)}$ Vs I_{DS} Characteristic

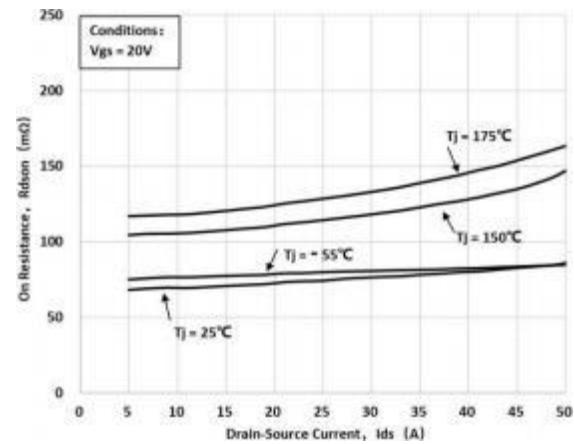


Fig 5: $R_{DS(on)}$ vs. Temperature

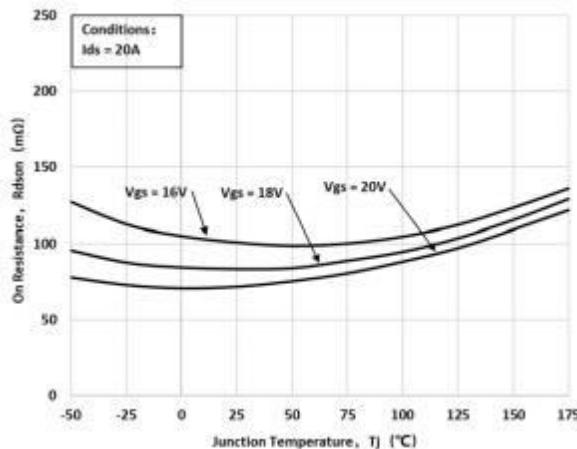
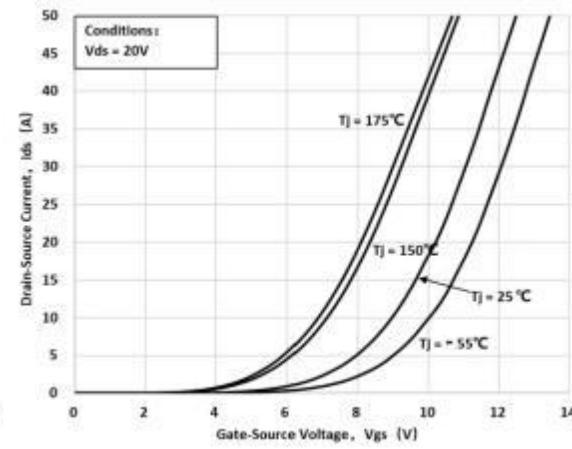


Fig 6: Transfer Characteristic





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Fig 7: Body-diode Characteristic ($T_J = -55^\circ\text{C}$)

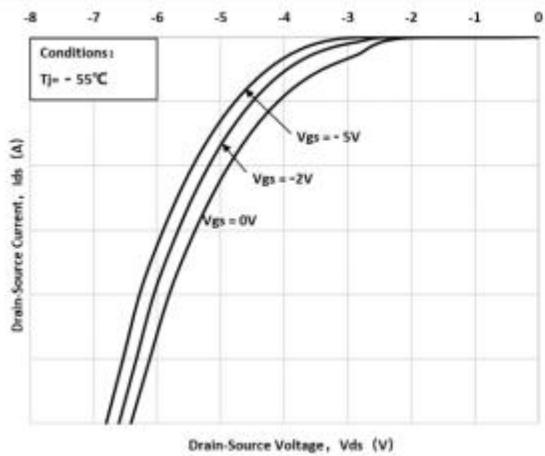


Fig 8: Body-diode Characteristic ($T_J = 25^\circ\text{C}$)

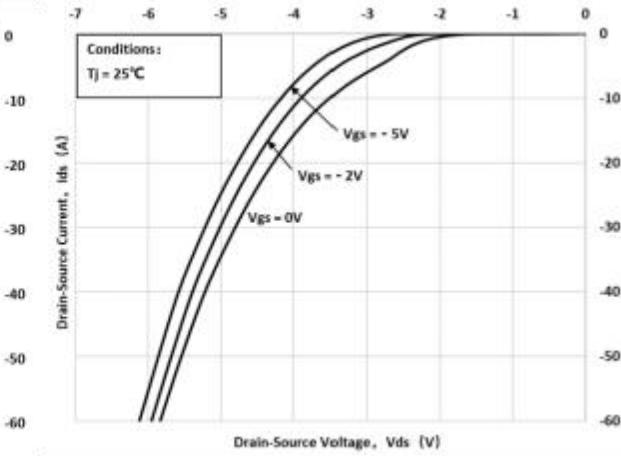


Fig 9: Body-diode Characteristic ($T_J = 175^\circ\text{C}$)

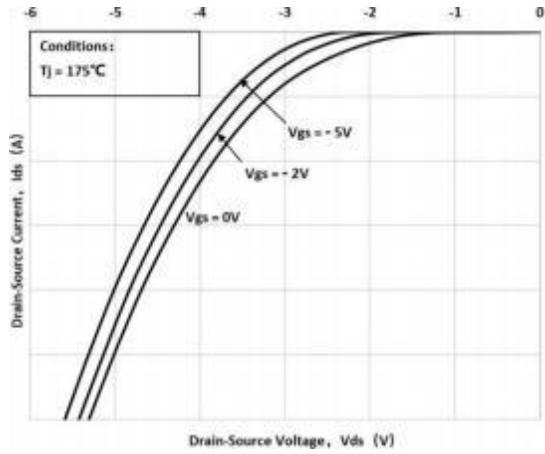


Fig 10: V_{TH} Vs T_J Temperature Characteristic

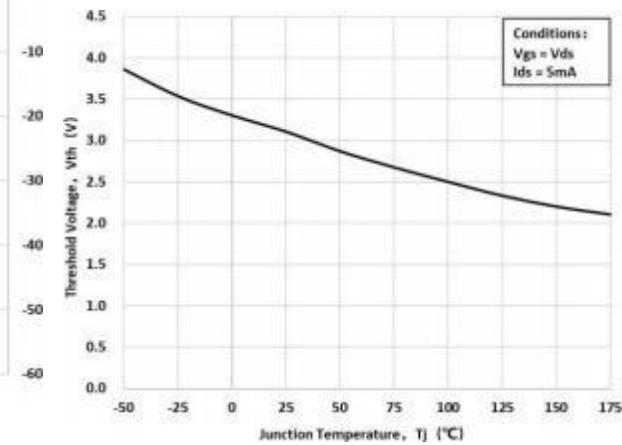


Fig 11: Gate Charge Characteristics

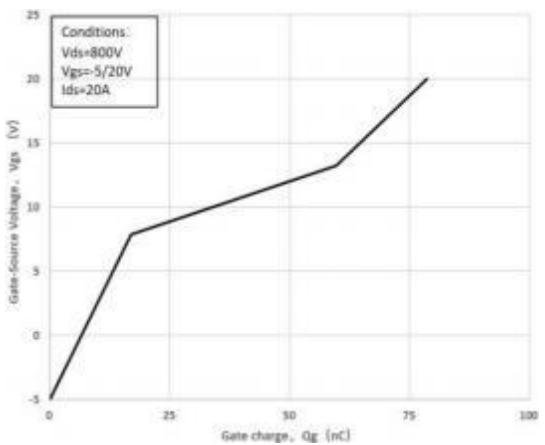
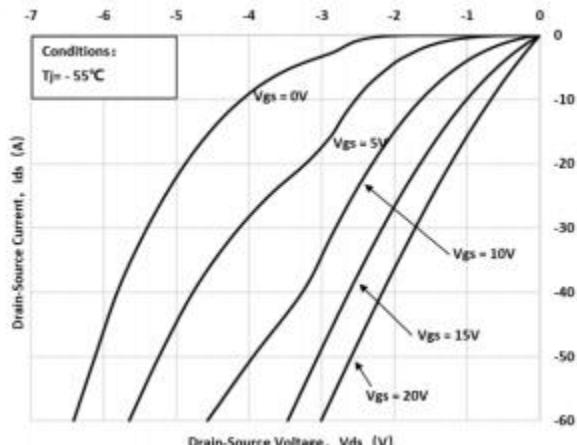


Fig 12: 3rd Quadrant Characteristic ($T_J = -55^\circ\text{C}$)





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Fig 13: 3rd Quadrant Characteristic($T_J=25^\circ\text{C}$)

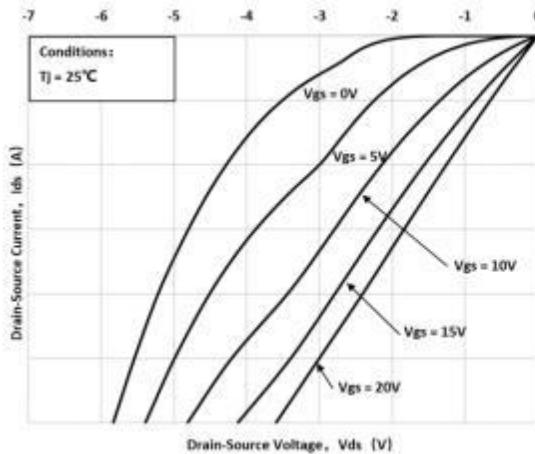


Fig 14: 3rd Quadrant Characteristic($T_J=175^\circ\text{C}$)

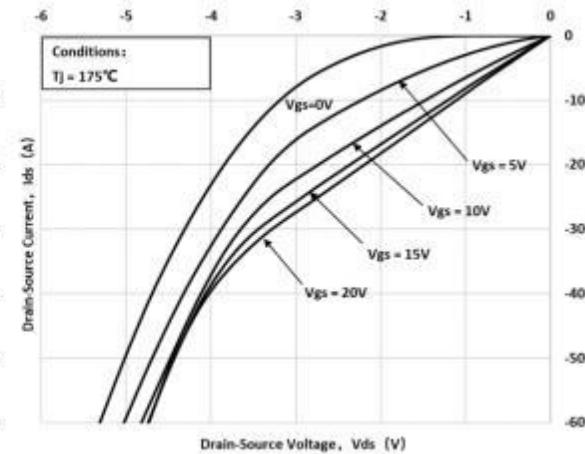


Fig 15: Capacitance Characteristic

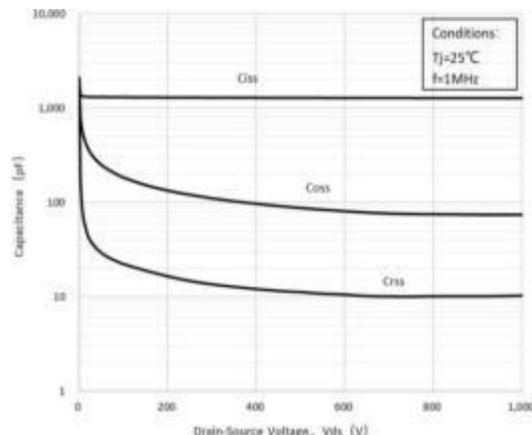


Fig 16: Safe Operating Area

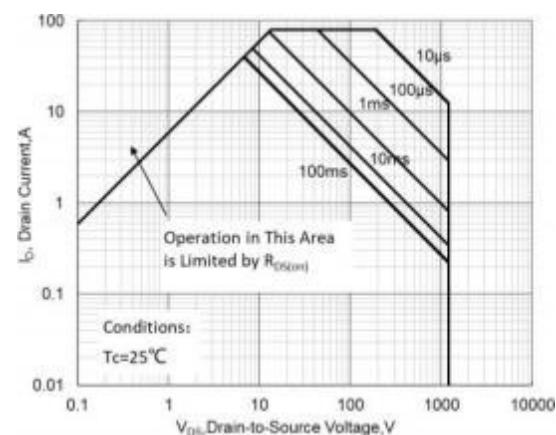
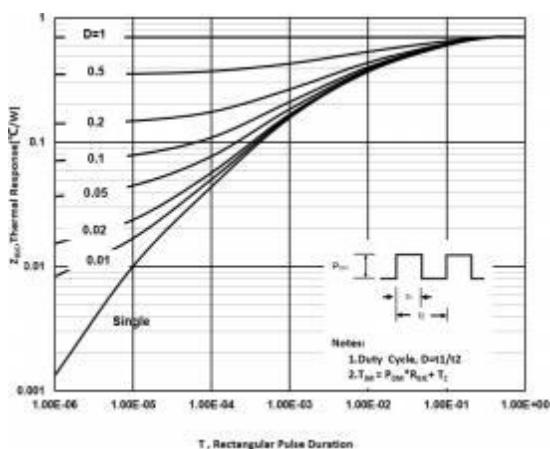


Fig 17 : Transient Thermal Impedance

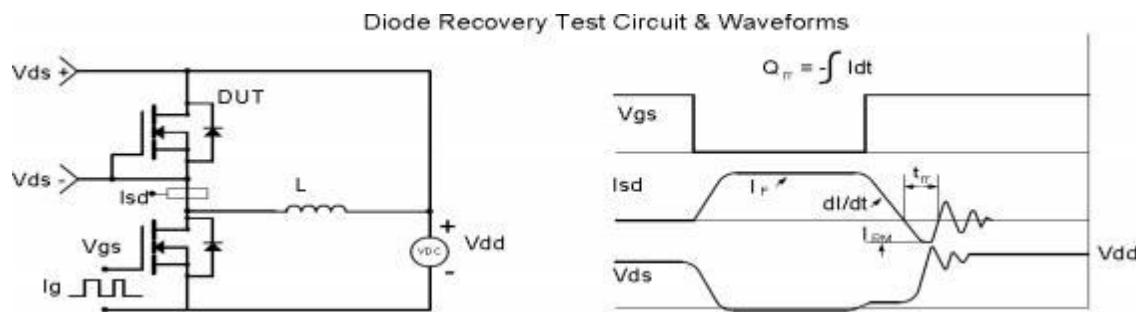
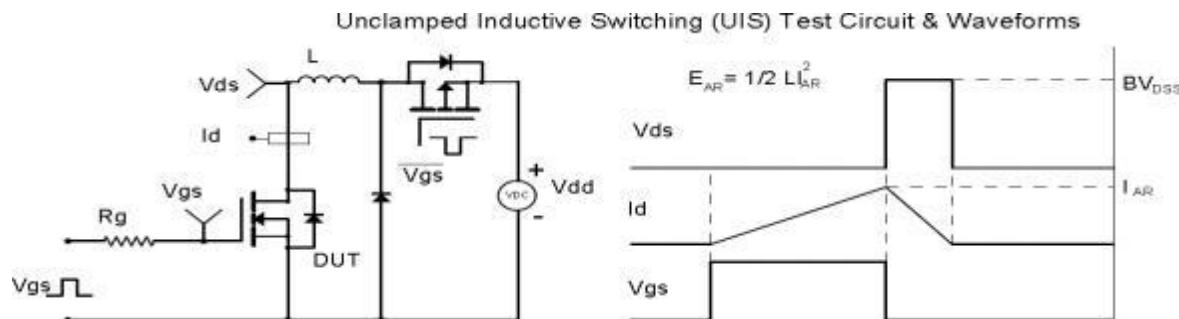




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Test Circuit & Waveform

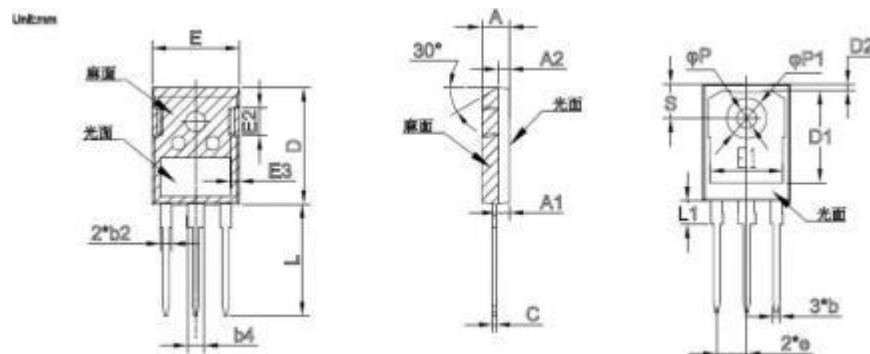




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Package Outline:



TO247-3L						
	Min	Nom	Max		Min	Nom
A	4.70	5.00	5.20	E1	13.06	13.26
A1	2.30		2.50	E2	4.90	5.00
A2	1.90	2.00	2.10	E3	1.50	1.80
b	1.10	1.20	1.30	e	5.34	5.44
b2		2.00		L	19.80	20.00
b4		3.00		L1		4.17
C	0.5	0.6	0.7	P	3.50	3.60
D	20.8	20.95	21.1	P1	7.00	7.19
D1		16.55		S	6.04	6.15
D2	0.95	1.17	1.35			
E	15.48	15.88	16.28			

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.